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			Application Number	10/575,876	
			Confirmation Number	2221	
			Filing Date	April 17, 2006	
			First Named Inventor	Robert Ian Renton BLYTH	
			Art Unit	Not Yet Known	
			Examiner Name	Not Yet Known	
Sheet	1	of	1	Attorney Docket Number	Q94363

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code <sup>2</sup> (if known)		
		US			
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FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation <sup>6</sup>
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)			
/A.B./		WO	0069625		11/23/2000	The University of Southern California,	

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation <sup>6</sup>
/A.B./		Energy Level Alignment and Interfacial Electronic Structures at Organic/Metal and Organic/Organic Interfaces**; Ishii, et al. Advanced Materials 1999, 11, No. 8	
↓		Photoemission studies of functional organic materials and their interfaces; Seki, et al.; Journal of Electron Spectroscopy and Related Phenomena; 88-91 (1998) 821-830	
↓		Molecular Level Alignment at Organic Semiconductor-metal Interfaces; Hill, et al.; Applied Physics Letters; Volume 73, Number 5, August 3, 1998	
↓		Band alignment at the organic-inorganic interface; Koller, et al.; Applied Physics Letters; Volume 76, Number 7, February 14, 2000	
↓		Band alignment in organic devices: Photoemission studies of model oligomers on In <sub>2</sub> O <sub>3</sub> , Blyth, et al.; Journal of Applied Physics; Volume 90, Number 1, July 1, 2001	

Examiner Signature	/Allison Bourke/	Date Considered	08/31/2009
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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